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				Application Number	10/591,945-Conf. #8000
				Filing Date	September 8, 2006
				First Named Inventor	Hiroshi FUJISAWA
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	1752-0187PUS1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
/NI/	AA*	US-20020043530-A1	04-18-2002	Ito	
	AB*	US-20030015521-A1	01-23-2003	Ito	
V	AC*	US-5,648,814	07-08-1997	Shamoulian et al.	
V	AD*	US-20020006680-A1	01-17-2002	Kataia et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)			
/NI/	BA	JP-2000-502509-A	02-29-2000		
V	BB	WO-97/23945-A1	07-03-1997		
V	BC	JP-2838810-B	10-16-1998		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(e)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. \* Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
/NI/	CA	Partial English language translation of JP-10-223742 (1998-08-21).			
	CB	ASANO et al., Fundamental Study of an Electrostatic Chuck for Silicon Wafer Handling, Conference Record of the 1997 IEEE Industry Applications Conference, Vol. 3, pp. 1998-2003, (1998).			
	CC	English language abstract of JP 6-302678 (1994-10-28).			
	CD	English language abstract of JP 2002-124446 (2002-04-26).			
	CE	English language abstract of JP 6-203991 (1996-08-09).			
	CF	English language abstract of JP 2002-028113 (2002-01-25).			
	CG	English language abstract of JP 2003-179128 (2003-06-27).			
	CH	English language abstract of JP 2004-031584 (2004-01-29).			
	CI	English language abstract of JP 2003-318251 (2003-11-07).			
	CJ	English language abstract of JP 2004-031599 (2004-01-29).			
V	CK	English language abstract of JP 6-064663 (1996-03-08).			
V	CL	English language abstract of JP 11-251417 (1999-09-17).			

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Examiner Signature	/Nicholas Ieva/	Date Considered	09/24/2007
Birch, Stewart, Kolasch & Birch, LLP GMM/TK/enm			